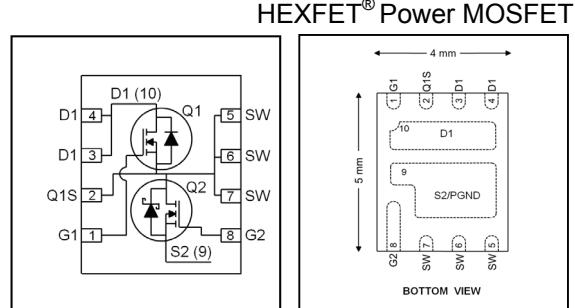


	Q1	Q2	
V_{DSS}	25	25	V
R_{DS(on)} max (@V _{GS} = 4.5V)	4.70	1.80	mΩ
Q_g (typical)	9.7	23	nC
I_D (@T _c = 25°C)	25⑦	25⑦	A



Applications

- Control and Synchronous MOSFETs for synchronous buck converters

Features

Control and synchronous MOSFETs in one package

Low charge control MOSFET (9.7nC typical)

Low R_{DS(on)} synchronous MOSFET (<1.8mΩ)

Intrinsic Schottky Diode with Low Forward Voltage on Q2

RoHS Compliant, Halogen-Free

MSL1, Industrial Qualification

Benefits

Increased power density

Lower switching losses

Lower conduction losses

Lower Switching Losses

Environmentally friendlier

Increased reliability

results in
⇒

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRFH4257DPbF	Dual PQFN 5mm x 4mm	Tape and Reel	4000	IRFH4257DTRPbF

Absolute Maximum Ratings

	Parameter	Q1 Max.	Q2 Max.	Units
V _{GS}	Gate-to-Source Voltage	± 20		V
I _D @ T _c = 25°C	Continuous Drain Current, V _{GS} @ 4.5V	68⑥⑦	111⑥⑦	A
I _D @ T _c = 70°C	Continuous Drain Current, V _{GS} @ 4.5V	54⑥⑦	88⑥⑦	
I _D @ T _c = 25°C	Continuous Drain Current, V _{GS} @ 4.5V (Source Bonding Technology Limited)	25⑦	25⑦	
I _{DM}	Pulsed Drain Current	120⑧	375⑧	
P _D @ T _c = 25°C	Power Dissipation	25	28	W
P _D @ T _c = 70°C	Power Dissipation	16	18	
	Linear Derating Factor	0.20	0.22	W/°C
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to + 150		°C

Thermal Resistance

	Parameter	Q1 Max.	Q2 Max.	Units
R _{θJC} (Bottom)	Junction-to-Case ④	5.0	4.5	°C/W
R _{θJC} (Top)	Junction-to-Case ④	33	26	
R _{θJA}	Junction-to-Ambient ⑤	45	40	
R _{θJA} (<10s)	Junction-to-Ambient ⑤	30	27	

Notes ① through ⑧ are on page 12

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

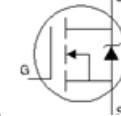
	Parameter		Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	Q1	25	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
		Q2	25	—	—		$V_{\text{GS}} = 0\text{V}, I_D = 1.0\text{mA}$
$\Delta V_{\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	Q1	—	22	—	mV/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1.0\text{mA}$
		Q2	—	22	—		Reference to $25^\circ\text{C}, I_D = 10\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	Q1	—	2.7	3.4	m Ω	$V_{\text{GS}} = 10\text{V}, I_D = 25\text{A}$ ③
		Q2	—	1.1	1.4		$V_{\text{GS}} = 10\text{V}, I_D = 25\text{A}$ ③
		Q1	—	3.7	4.7		$V_{\text{GS}} = 4.5\text{V}, I_D = 25\text{A}$ ③
		Q2	—	1.4	1.8		$V_{\text{GS}} = 4.5\text{V}, I_D = 25\text{A}$ ③
$V_{\text{GS(th)}}$	Gate Threshold Voltage	Q1	1.1	1.6	2.1	V	Q1: $V_{\text{DS}} = V_{\text{GS}}, I_D = 35\mu\text{A}$
		Q2	1.1	1.6	2.1		Q2: $V_{\text{DS}} = V_{\text{GS}}, I_D = 100\mu\text{A}$
$\Delta V_{\text{GS(th)}}/\Delta T_J$	Gate Threshold Voltage Coefficient	Q1	—	-5.4	—	mV/ $^\circ\text{C}$	Q1: $V_{\text{DS}} = V_{\text{GS}}, I_D = 35\mu\text{A}$
		Q2	—	-5.3	—		Q2: $V_{\text{DS}} = V_{\text{GS}}, I_D = 1\text{mA}$
I_{DSS}	Drain-to-Source Leakage Current	Q1	—	—	1.0	μA	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$
		Q2	—	—	250		$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 0\text{V}$
I_{GSS}	Gate-to-Source Forward Leakage	Q1	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
		Q2	—	—	100		$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	Q1	—	—	-100		$V_{\text{GS}} = -20\text{V}$
		Q2	—	—	-100		$V_{\text{GS}} = -20\text{V}$
g_{fs}	Forward Transconductance	Q1	100	—	—	S	$V_{\text{DS}} = 10\text{V}, I_D = 25\text{A}$
		Q2	138	—	—		$V_{\text{DS}} = 10\text{V}, I_D = 25\text{A}$
Q_g	Total Gate Charge	Q1	—	9.7	15	nC	Q1 $V_{\text{DS}} = 13\text{V}$ $V_{\text{GS}} = 4.5\text{V}, I_D = 25\text{A}$
		Q2	—	23	35		
Q_{gs1}	Pre-V _{th} Gate-to-Source Charge	Q1	—	2.4	—		
		Q2	—	5.1	—		
Q_{gs2}	Post-V _{th} Gate-to-Source Charge	Q1	—	1.2	—		
		Q2	—	2.6	—		
Q_{gd}	Gate-to-Drain Charge	Q1	—	3.4	—		
		Q2	—	7.6	—		
Q_{godr}	Gate Charge Overdrive	Q1	—	2.7	—		
		Q2	—	7.7	—		
Q_{sw}	Switch Charge ($Q_{\text{gs2}} + Q_{\text{gd}}$)	Q1	—	4.6	—		
		Q2	—	10.2	—		
Q_{oss}	Output Charge	Q1	—	10	—	nC	$V_{\text{DS}} = 16\text{V}, V_{\text{GS}} = 0\text{V}$
		Q2	—	25	—		
R_G	Gate Resistance	Q1	—	1.4	—	Ω	
		Q2	—	0.7	—		
$t_{\text{d(on)}}$	Turn-On Delay Time	Q1	—	8.2	—	ns	Q1 $V_{\text{DS}} = 13\text{V}$ $V_{\text{GS}} = 4.5\text{V}$ $I_D = 25\text{A}, R_g = 1.8\Omega$
		Q2	—	12	—		
t_r	Rise Time	Q1	—	47	—		
		Q2	—	51	—		
$t_{\text{d(off)}}$	Turn-Off Delay Time	Q1	—	12	—		
		Q2	—	20	—		
t_f	Fall Time	Q1	—	20	—		
		Q2	—	25	—		
C_{iss}	Input Capacitance	Q1	—	1321	—	pF	$V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 13\text{V}$ $f = 1.0\text{MHz}$
		Q2	—	3161	—		
C_{oss}	Output Capacitance	Q1	—	365	—		
		Q2	—	965	—		
C_{iss}	Reverse Transfer Capacitance	Q1	—	101	—		
		Q2	—	237	—		

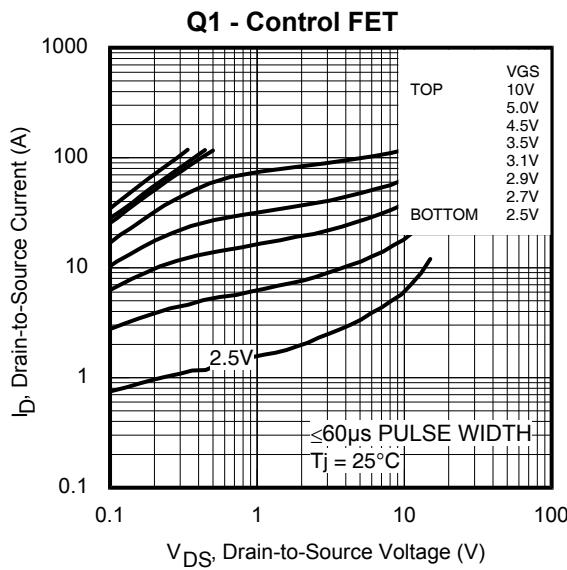
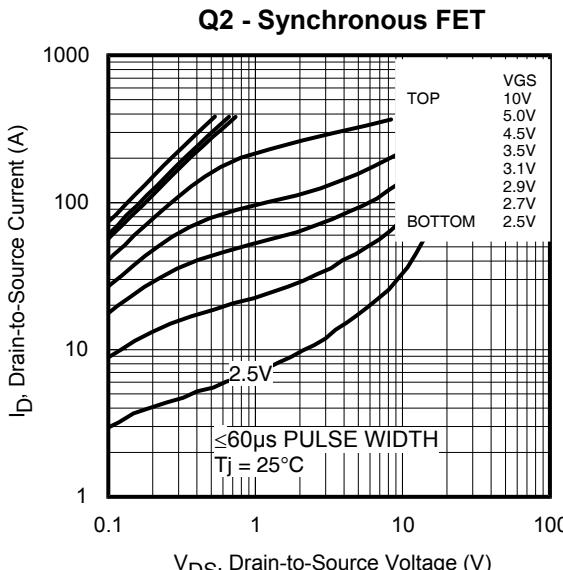
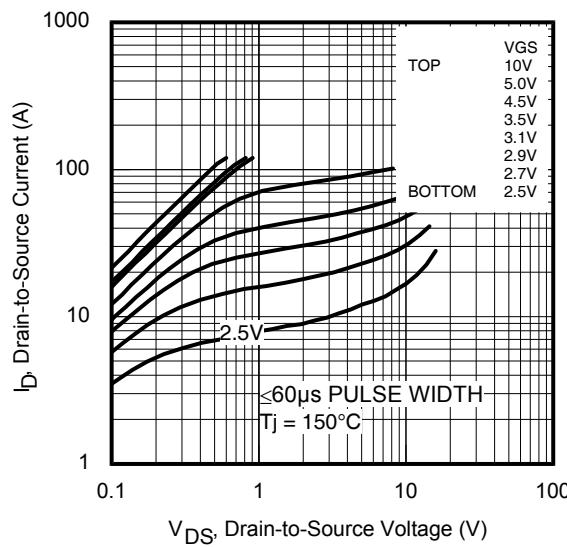
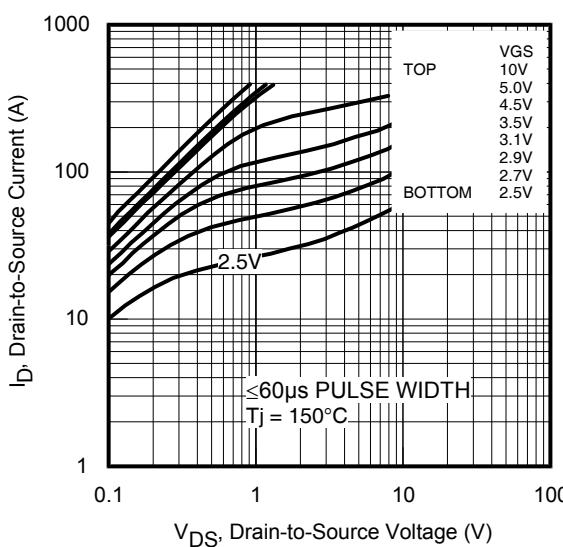
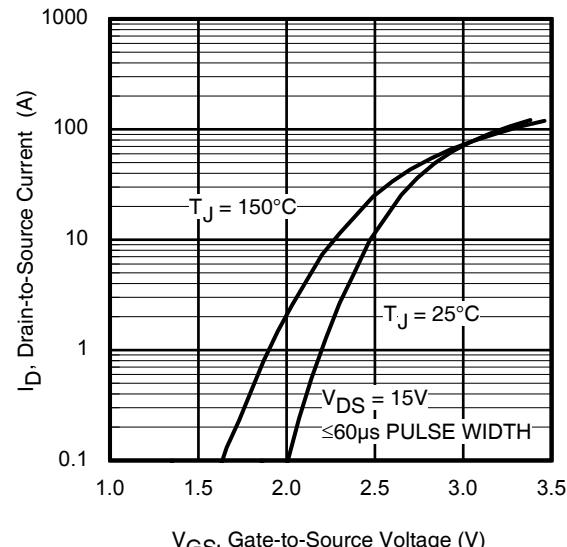
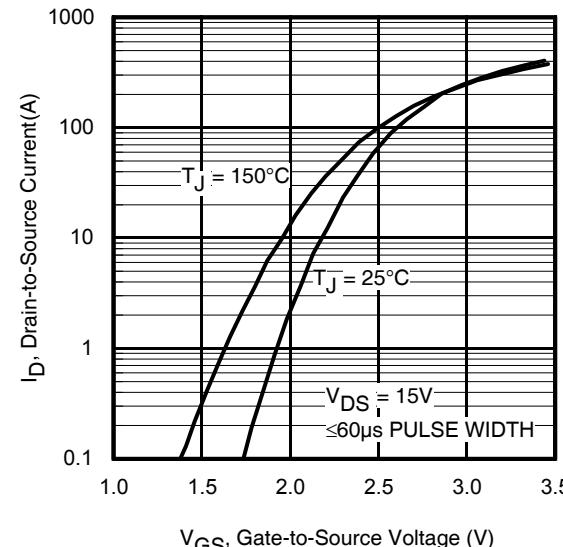
Avalanche Characteristics

	Parameter	Typ.	Q1 Max.	Q2 Max.	Units
E _{AS}	Single Pulse Avalanche Energy ②	—	42	387	mJ

Diode Characteristics

	Parameter		Min.	Typ.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)	Q1	—	—	25⑦	A	MOSFET symbol showing the integral reverse p-n junction diode.
		Q2	—	—	25⑦		
I _{SM}	Pulsed Source Current (Body Diode)	Q1	—	—	120⑧	A	T _J = 25°C, I _S = 25A, V _{GS} = 0V ③
		Q2	—	—	375⑧		
V _{SD}	Diode Forward Voltage	Q1	—	—	1.0	V	T _J = 25°C, I _S = 25A, V _{GS} = 0V ③
		Q2	—	—	0.75		
t _{rr}	Reverse Recovery Time	Q1	—	18	—	ns	Q1 T _J = 25°C, I _F = 25A V _{DD} = 13V, di/dt = 200A/μs ③
		Q2	—	30	—		
Q _{rr}	Reverse Recovery Charge	Q1	—	16	—	nC	Q2 T _J = 25°C, I _F = 25A V _{DD} = 13V, di/dt = 200A/μs ③
		Q2	—	37	—		



**Fig 1.** Typical Output Characteristics**Fig 2.** Typical Output Characteristics**Fig 3.** Typical Output Characteristics**Fig 4.** Typical Output Characteristics**Fig 5.** Typical Transfer Characteristics**Fig 6.** Typical Transfer Characteristics

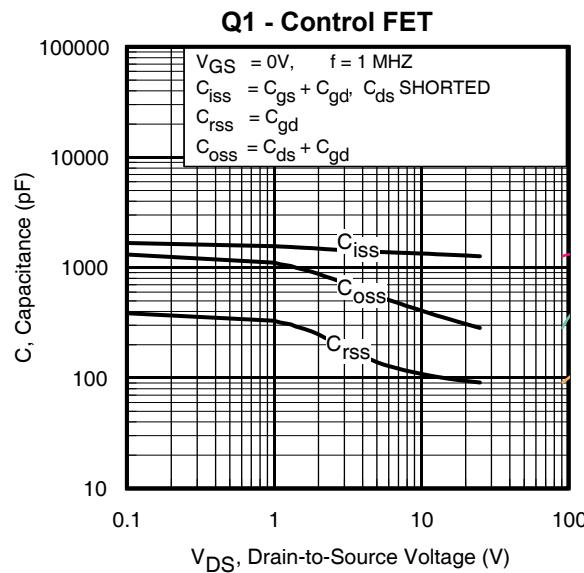


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

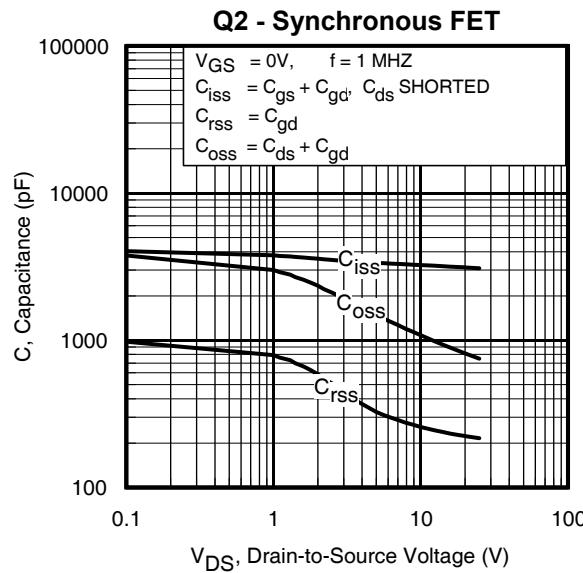


Fig 8. Typical Capacitance vs. Drain-to-Source Voltage

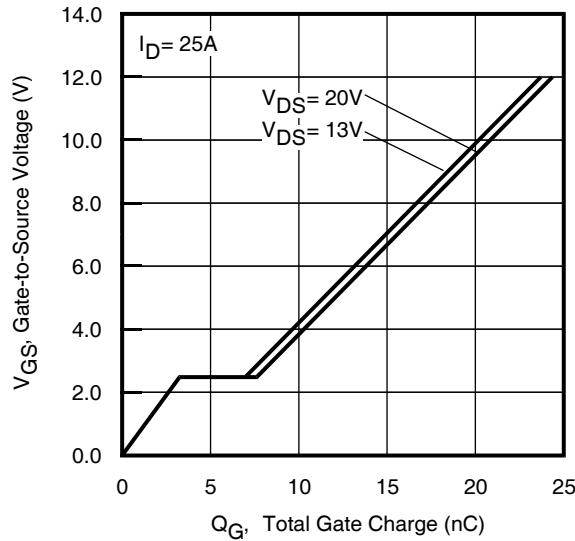


Fig 9. Typical Gate Charge vs. Gate-to-Source Voltage

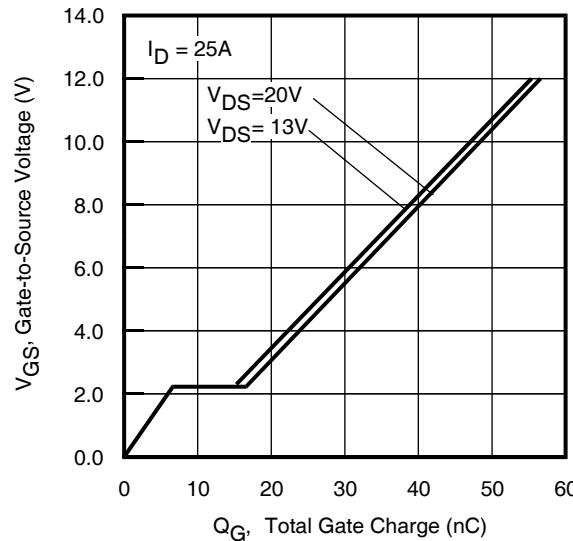


Fig 10. Typical Gate Charge vs. Gate-to-Source Voltage

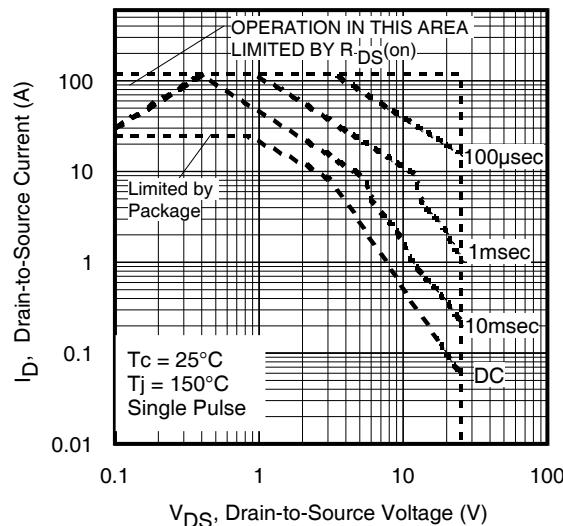


Fig 11. Maximum Safe Operating Area

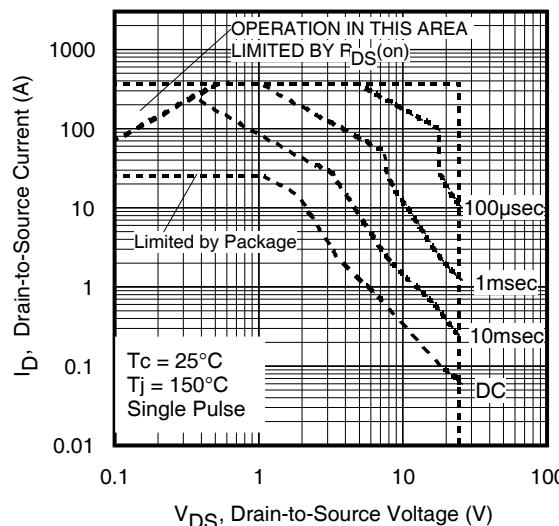


Fig 12. Maximum Safe Operating Area

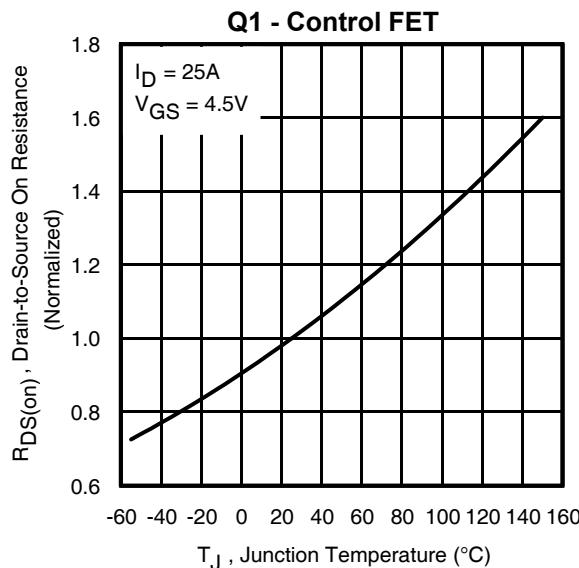


Fig 13. Normalized On-Resistance vs. Temperature

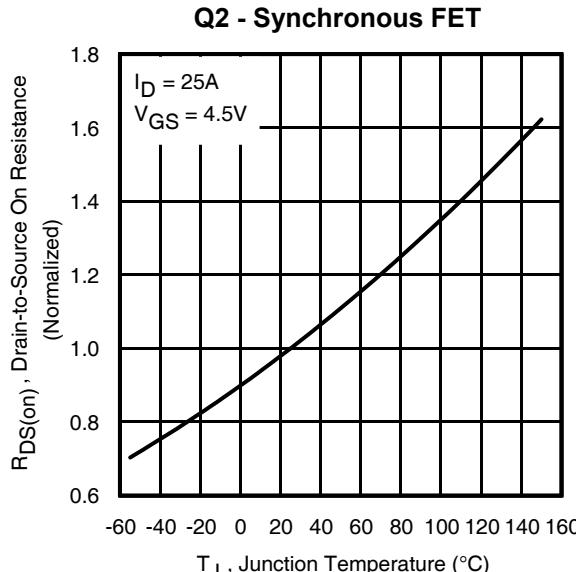
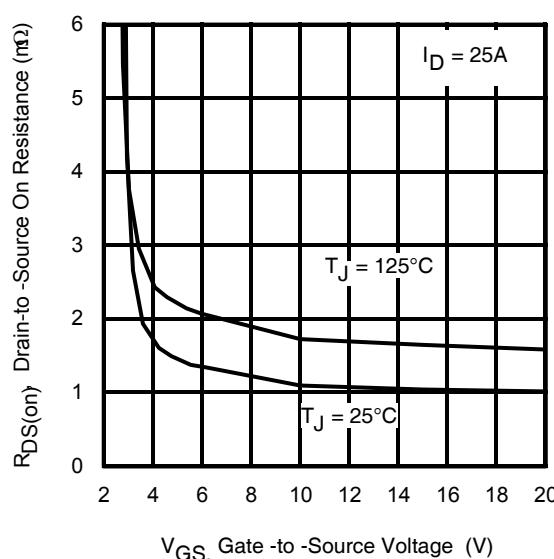
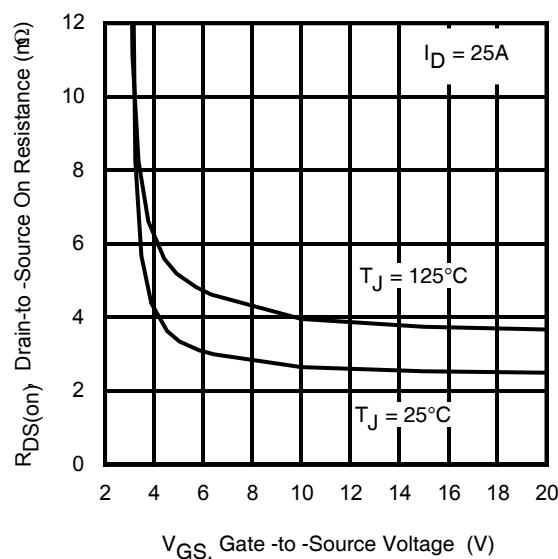
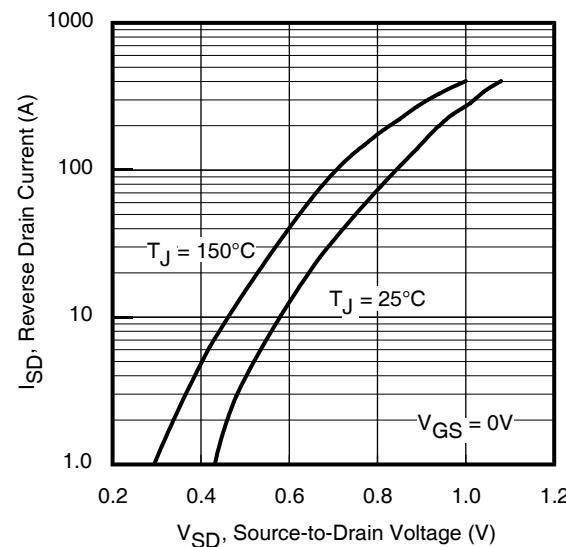
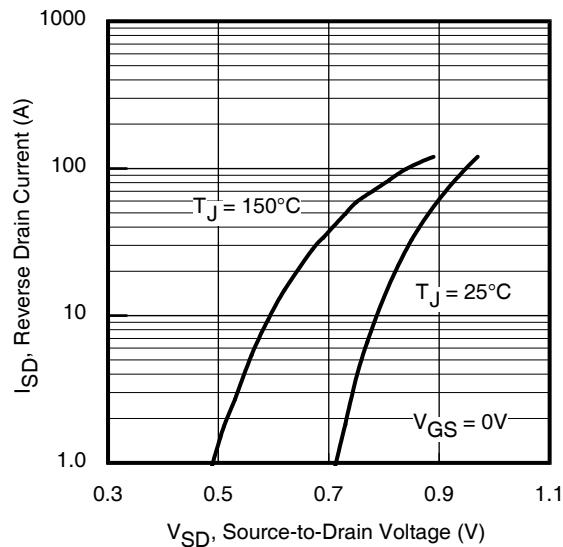
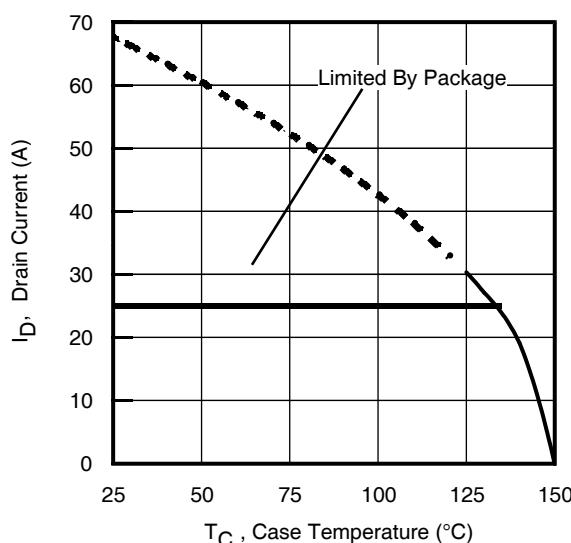
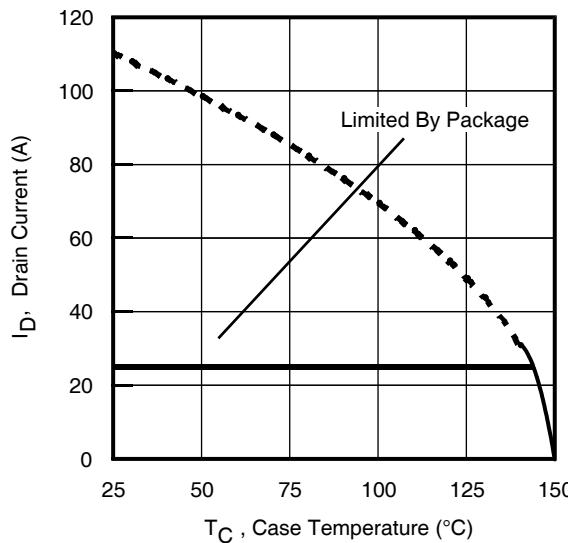
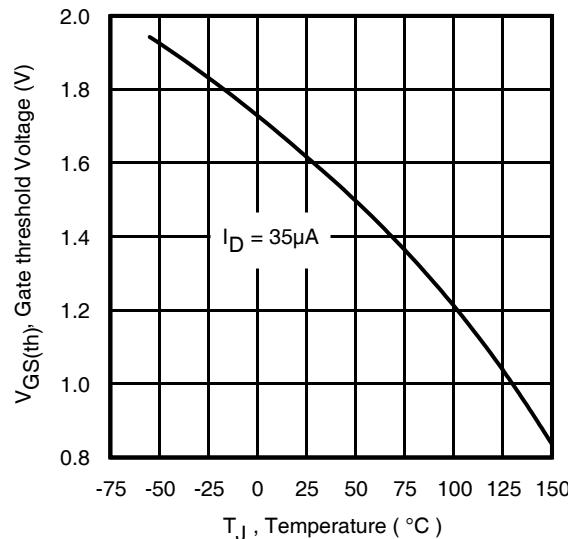
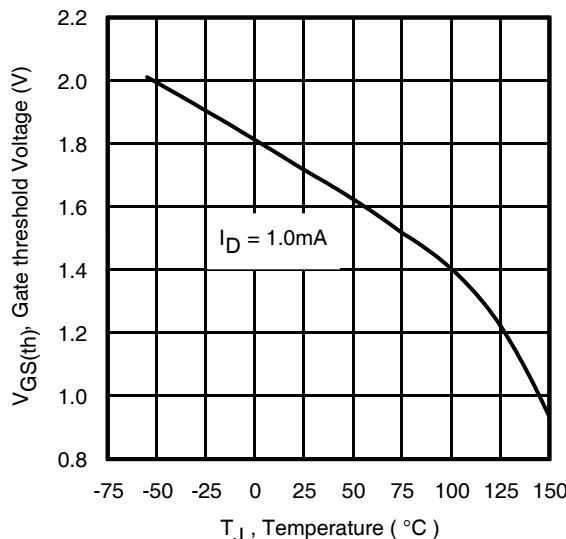
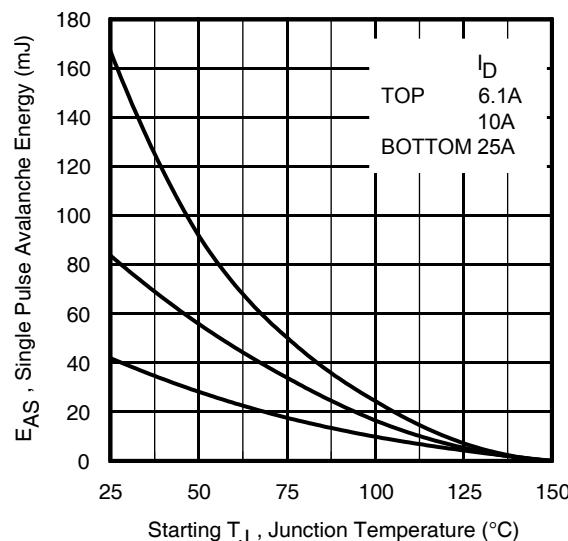
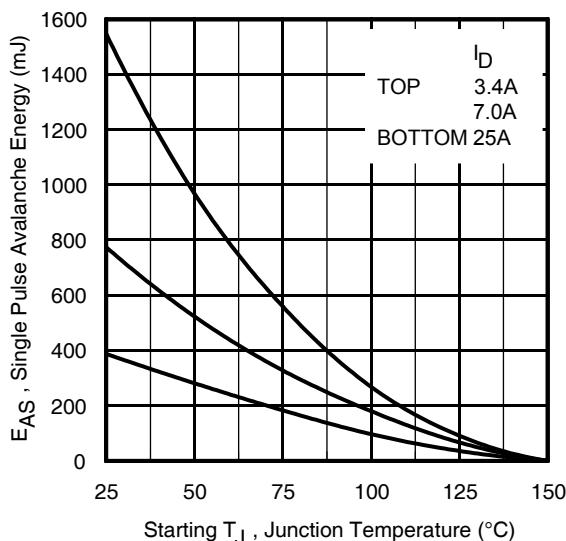


Fig 14. Normalized On-Resistance vs. Temperature



Q1 - Control FET**Fig 19. Maximum Drain Current vs. Case Temperature****Q2 - Synchronous FET****Fig 20. Maximum Drain Current vs. Case Temperature****Fig 21. Threshold Voltage vs. Temperature****Fig 22. Threshold Voltage vs. Temperature****Fig 23. Maximum Avalanche Energy vs. Drain Current****Fig 24. Maximum Avalanche Energy vs. Drain Current**

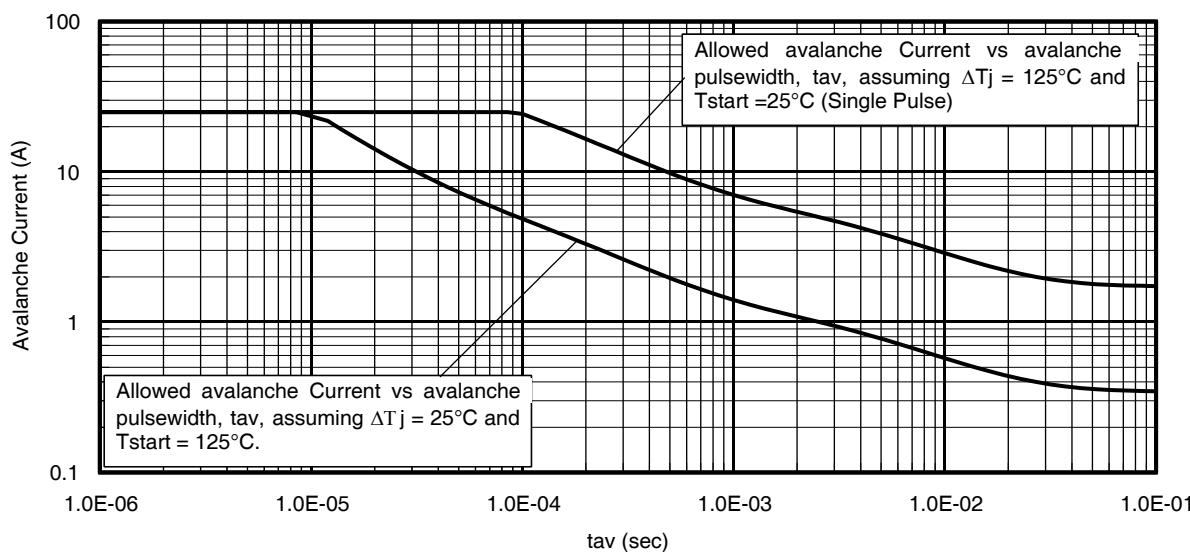


Fig 25. Typical Avalanche Current vs. Pulse Width (Q1)

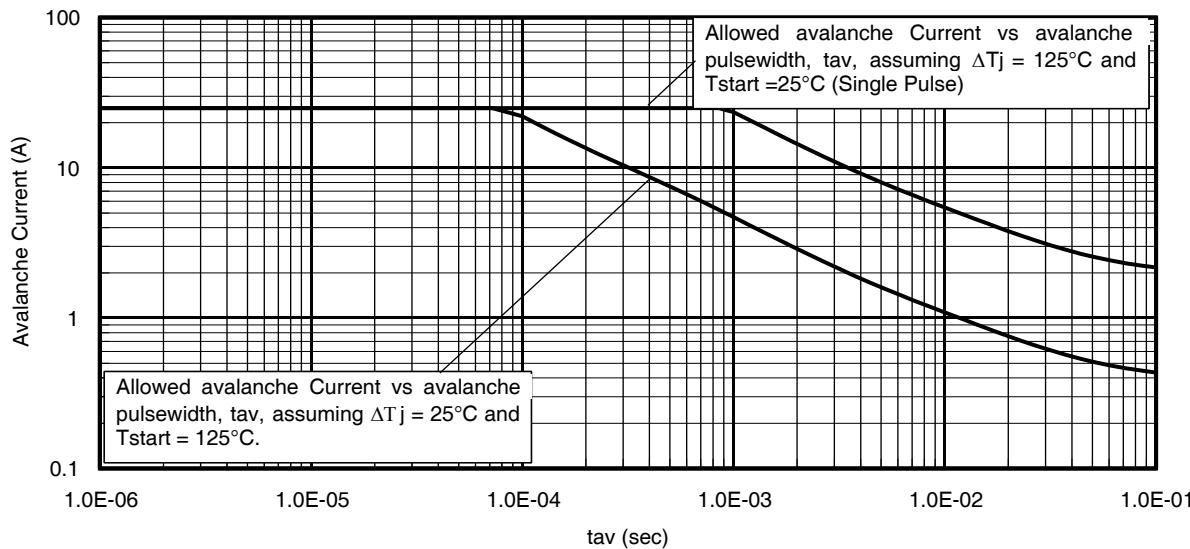


Fig 26. Typical Avalanche Current vs. Pulse Width (Q2)

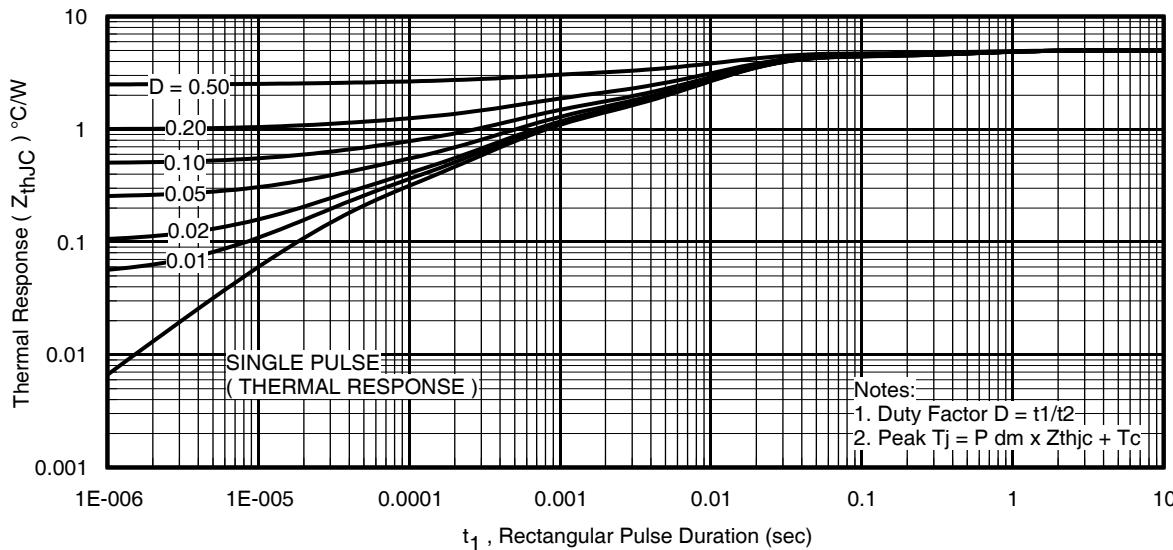


Fig 27. Maximum Effective Transient Thermal Impedance, Junction-to-Case (Q1)

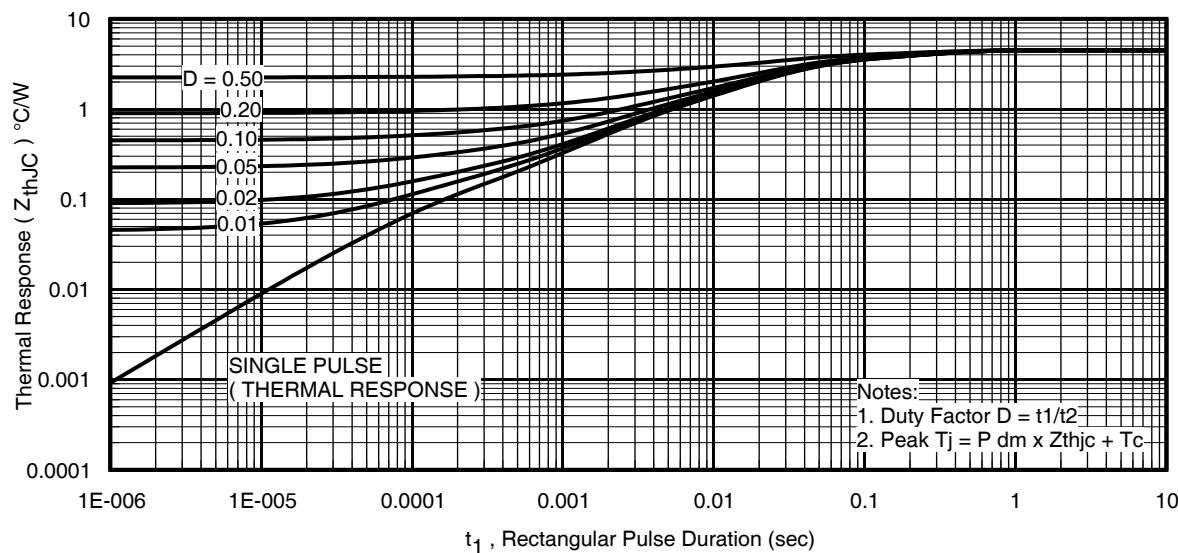


Fig 28. Maximum Effective Transient Thermal Impedance, Junction-to-Case (Q2)

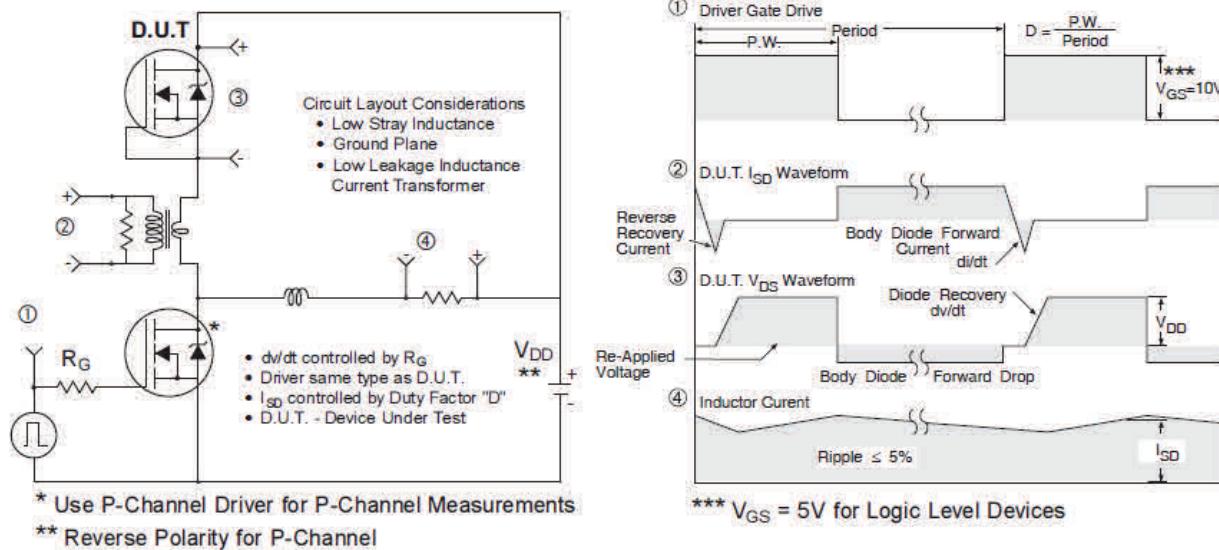


Fig 29. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

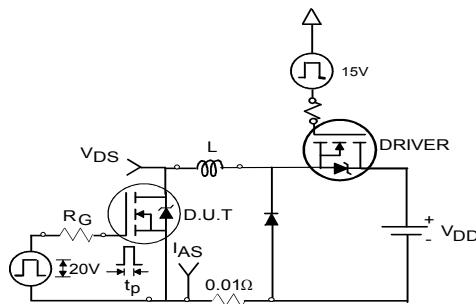


Fig 30a. Unclamped Inductive Test Circuit

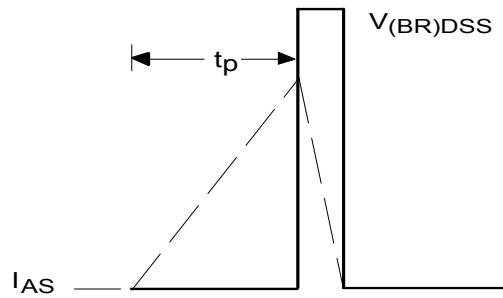


Fig 30b. Unclamped Inductive Waveforms

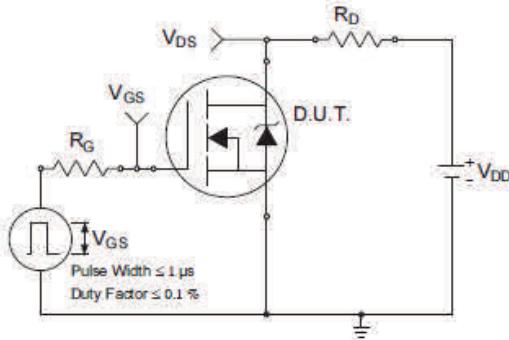


Fig 31a. Switching Time Test Circuit

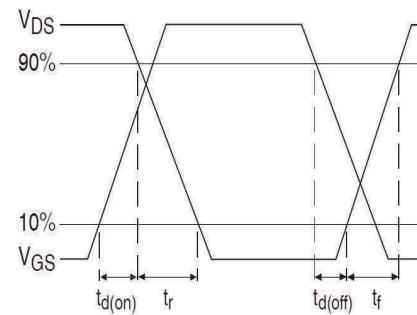


Fig 31b. Switching Time Waveforms

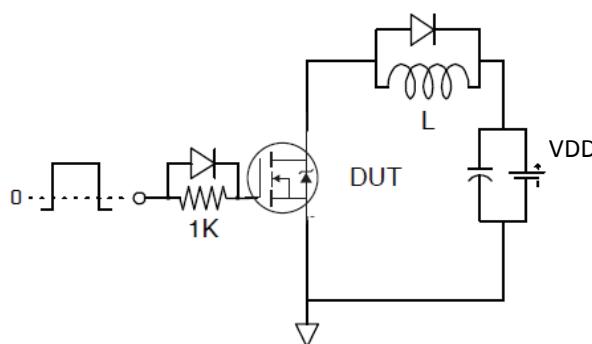


Fig 32a. Gate Charge Test Circuit

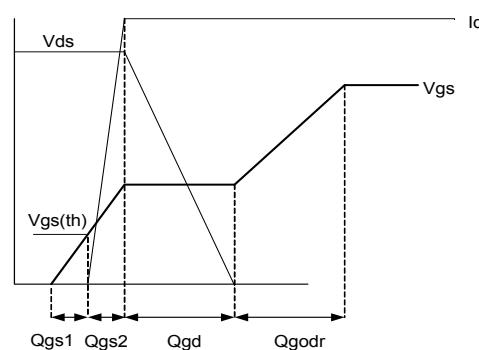
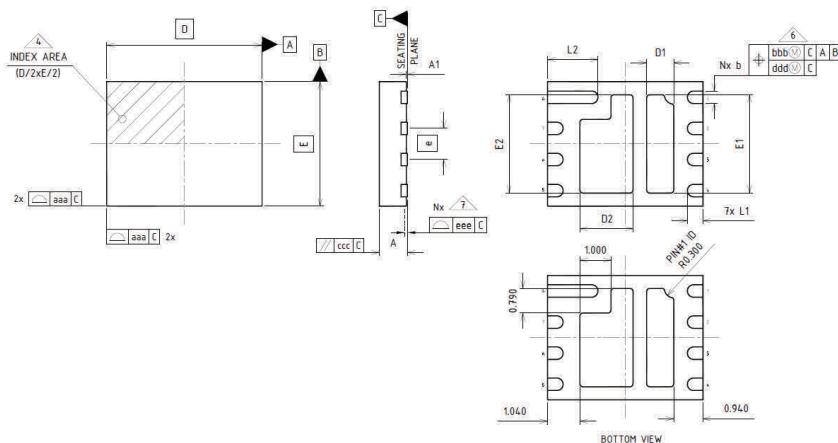


Fig 32b. Gate Charge Waveform

Dual PQFN 5x4 Package Details

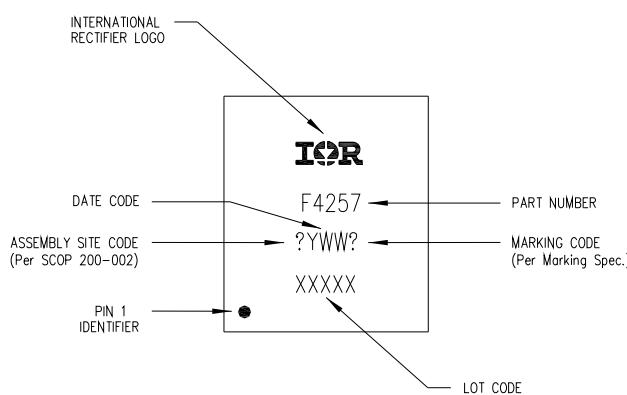


Thickness Symbol	Dimension Table			NOTE
	MINIMUM	NOMINAL	MAXIMUM	
A	0.80	0.90	1.00	
A1	0.00	0.02	0.05	
b	0.30	0.40	0.45	6
D	5.00	BSC		
E	4.00	BSC		
e	1.00	BSC		
D1	0.72	0.87	0.97	
E1	3.01	3.16	3.26	
D2	1.56	1.71	1.81	
E2	3.01	3.16	3.26	
L1	0.40	0.50	0.60	
L2	1.562	1.662	1.762	
aaa	0.05			
bbb	0.10			
ccc	0.10			
ddd	0.05			
eee	0.08			
N	8			3
NE	4			5
NOTES	1, 2			
LF DWG NO.	B-3664			
REV.	5			

NOTE:

1. Dimensioning and tolerancing conform to ASME Y14.5-2009.
2. All dimensions are in millimeters.
3. N is the total number of terminals.
4. The location of marked terminal #1 identifier is within the hatched area..
5. NE refers to the maximum number of terminals on E side.
6. Dimension b applies to metallized terminal and is measured between 0.15mm and 0.30mm from the terminal tip. If the terminal has a radius on the other end of it, dimension b should not be measured in that radius area.
7. Coplanarity applies to the terminals and all other bottom surface metallization.

Dual PQFN 5x4 Part Marking

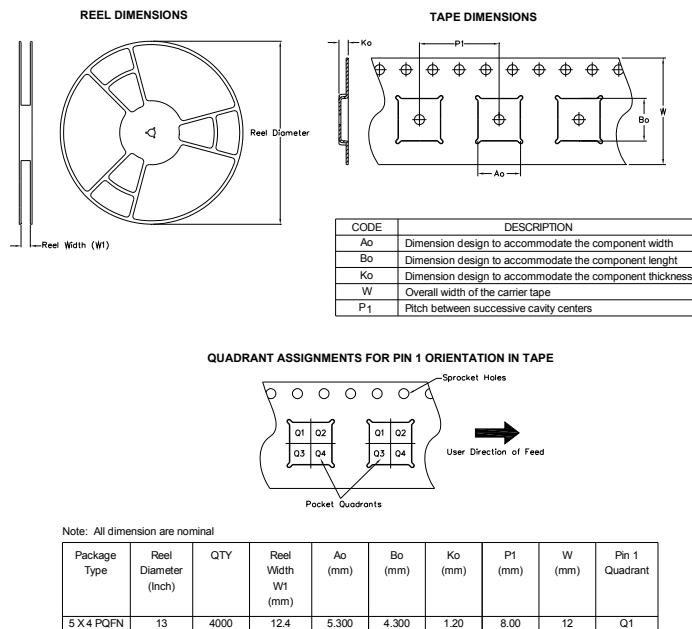


For more information on board mounting, including footprint and stencil recommendation, please refer to application note AN-1136: <http://www.irf.com/technical-info/appnotes/an-1136.pdf>

For more information on package inspection techniques, please refer to application note AN-1154: <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Dual PQFN 5x4 Outline Tape and Reel



Note: All dimension are nominal

Package Type	Reel Diameter (Inch)	QTY	Reel Width W1 (mm)	Ao (mm)	Bo (mm)	Ko (mm)	P1 (mm)	W (mm)	Pin 1 Quadrant
5 X 4 PQFN	13	4000	12.4	5.300	4.300	1.20	8.00	12	Q1

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>Qualification Information[†]

Qualification level	Industrial (per JEDEC JESD47F ^{††} guidelines)		
Moisture Sensitivity Level	DUAL PQFN 5mm x 4mm		MSL1 (per JEDEC J-STD-020D ^{††})
RoHS Compliant	Yes		

[†] Qualification standards can be found at International Rectifier's web site <http://www.irf.com/product-info/reliability>^{††} Applicable version of JEDEC standard at the time of product release.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}$,
- Q1: $L = 0.13\text{mH}$, $R_G = 50\Omega$, $I_{AS} = 25\text{A}$;
- Q2: $L = 1.24\text{mH}$, $R_G = 50\Omega$, $I_{AS} = 25\text{A}$.
- ③ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ R_θ is measured at T_J approximately 90°C .
- ⑤ When mounted on 1 inch square PCB (FR-4). Please refer to AN-994 for more details:
<http://www.irf.com/technical-info/appnotes/an-994.pdf>
- ⑥ Calculated continuous current based on maximum allowable junction temperature.
- ⑦ Current is limited to $Q1 = 25\text{A}$ & $Q2 = 25\text{A}$ by source bonding technology.
- ⑧ Pulsed drain current is limited to 100A by source bonding technology.

International
IR
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